Understanding Embedded - Microprocessors

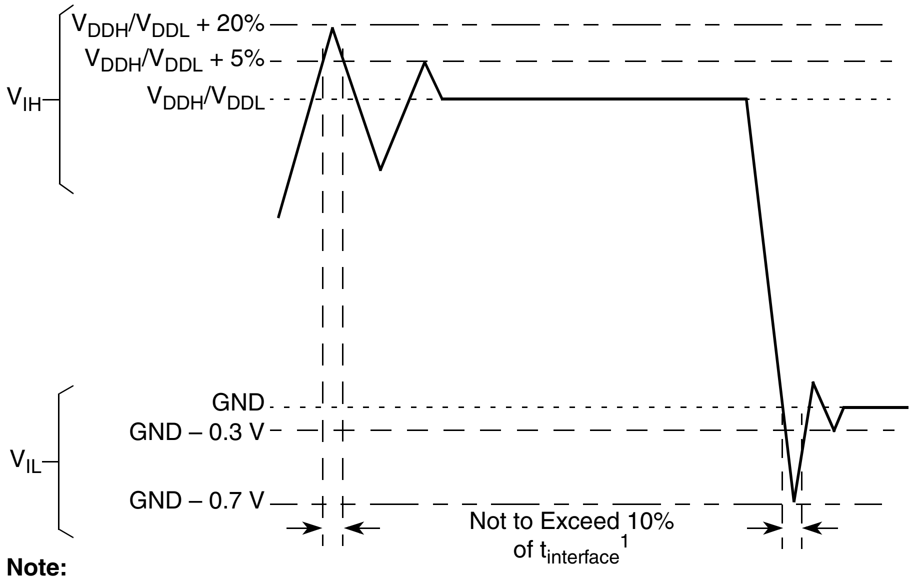
Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	50MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (4), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc860tvr50d4r2

Figure 1 shows the undershoot and overshoot voltages at the interface of the MPC860.



Note:
1. $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 1. Undershoot/Overshoot Voltage for V_{DDH} and V_{DDL}

4 Thermal Characteristics

Table 3. Package Description

Package Designator	Package Code (Case No.)	Package Description
ZP	5050 (1103-01)	PBGA 357 25*25*0.9P1.27
ZQ/VR	5058 (1103D-02)	PBGA 357 25*25*1.2P1.27

Table 4 shows the thermal characteristics for the MPC860.

Table 4. MPC860 Thermal Resistance Data

Rating	Environment		Symbol	ZP MPC860P	ZQ / VR MPC860P	Unit
Mold Compound Thickness				0.85	1.15	mm
Junction-to-ambient [1]	Natural convection	Single-layer board (1s)	$R_{\theta JA}$ [2]	34	34	°C/W
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	22	22	
	Airflow (200 ft/min)	Single-layer board (1s)	$R_{\theta JMA}$ [3]	27	27	
		Four-layer board (2s2p)	$R_{\theta JMA}$ [3]	18	18	
Junction-to-board [4]			$R_{\theta JB}$	14	13	
Junction-to-case [5]			$R_{\theta JC}$	6	8	
Junction-to-package top [6]	Natural convection		Ψ_{JT}	2	2	

1 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.

2 Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.

3 Per JEDEC JESD51-6 with the board horizontal.

4 Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. For exposed pad packages where the pad would be expected to be soldered, junction-to-case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance.

6 Thermal characterization parameter indicating the temperature difference between the package top and the junction temperature per JEDEC JESD51-2.

Table 6. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input leakage current, V_{in} = 3.6 V (except TMS, TRST, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input leakage current, V_{in} = 0 V (except TMS, TRST, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input capacitance[2]	C_{in}	—	20	pF
Output high voltage, I_{OH} = –2.0 mA, V_{DDH} = 3.0 V (except XTAL, XFC, and open-drain pins)	V_{OH}	2.4	—	V
Output low voltage I_{OL} = 2.0 mA, CLKOUT I_{OL} = 3.2 mA [3] I_{OL} = 5.3 mA [4] I_{OL} = 7.0 mA, TXD1/PA14, TXD2/PA12 I_{OL} = 8.9 mA, TS, TA, TEA, BI, BB, HRESET, SRESET	V_{OL}	—	0.5	V

1 V_{IL}(max) for the I^2C interface is 0.8 V rather than the 1.5 V as specified in the I^2C standard.

2 Input capacitance is periodically sampled.

3 A(0:31), TSIZ0/REG, TSIZ1, D(0:31), DP(0:3)/IRQ(3:6), RD/WR, BURST, RSV/IRQ2, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/TOUT1/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, TOUT2/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/TOUT3/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/TOUT4/CLK8/PA0, REJCT1/SPISEL/PB31, SPICLK/PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, SMSYN1/SDACK1/PB23, SMSYN2/SDACK2/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/RTS1/PB19, L1ST2/RTS2/PB18, L1ST3/L1RQB/PB17, L1ST4/L1RQA/PB16, BRGO3/PB15, RSTRT1/PB14, L1ST1/RTS1/DREQ0/PC15, L1ST2/RTS2/DREQ1/PC14, L1ST3/L1RQB/PC13, L1ST4/L1RQA/PC12, CTS1/PC11, TGATE1/CD1/PC10, CTS2/PC9, TGATE2/CD2/PC8, SDACK2/L1TSYNCB/PC7, L1RSYNCB/PC6, SDACK1/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

4 BDIP/GPL_B(5), BR, BG, FRZ/IRQ6, CS(0:5), CS(6)/CE(1)_B, CS(7)/CE(2)_B, WE0/BS_B0/IORD, WE1/BS_B1/IOWR, WE2/BS_B2/PCOE, WE3/BS_B3/PCWE, BS_A(0:3), GPL_A0/GPL_B0, OE/GPL_A1/GPL_B1, GPL_A(2:3)/GPL_B(2:3)/CS(2:3), UPWAITA/GPL_A4, UPWAITB/GPL_B4, GPL_A5, ALE_A, CE1_A, CE2_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/STS, OP3/MODCK2/DSDO, and BADDR(28:30)

where:

Ψ_{JT} = thermal characterization parameter

T_T = thermocouple temperature on top of package

P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International 805 East Middlefield Rd. Mountain View, CA 94043	(415) 964-5111
MIL-SPEC and EIA/JESD (JEDEC) Specifications (Available from Global Engineering Documents)	800-854-7179 or 303-397-7956
JEDEC Specifications	http://www.jedec.org

1. C.E. Triplett and B. Joiner, “An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module,” Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
2. B. Joiner and V. Adams, “Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling,” Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Layout Practices

Each V_{DD} pin on the MPC860 should be provided with a low-impedance path to the board’s supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the chip. The V_{DD} power supply should be bypassed to ground using at least four 0.1 µF-bypass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{DD} and GND should be kept to less than half an inch per capacitor lead. A four-layer board employing two inner layers as V_{CC} and GND planes is recommended.

All output pins on the MPC860 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of 6 inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the V_{CC} and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.

Figure 7 provides the timing for the synchronous input signals.

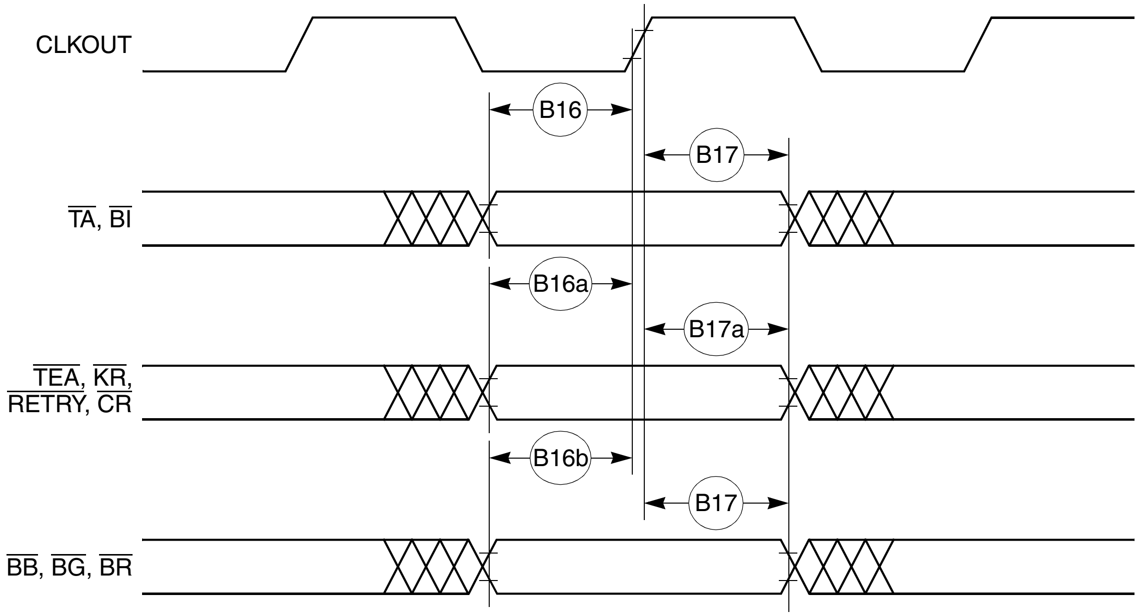


Figure 7. Synchronous Input Signals Timing

Figure 8 provides normal case timing for input data. It also applies to normal read accesses under the control of the UPM in the memory controller.

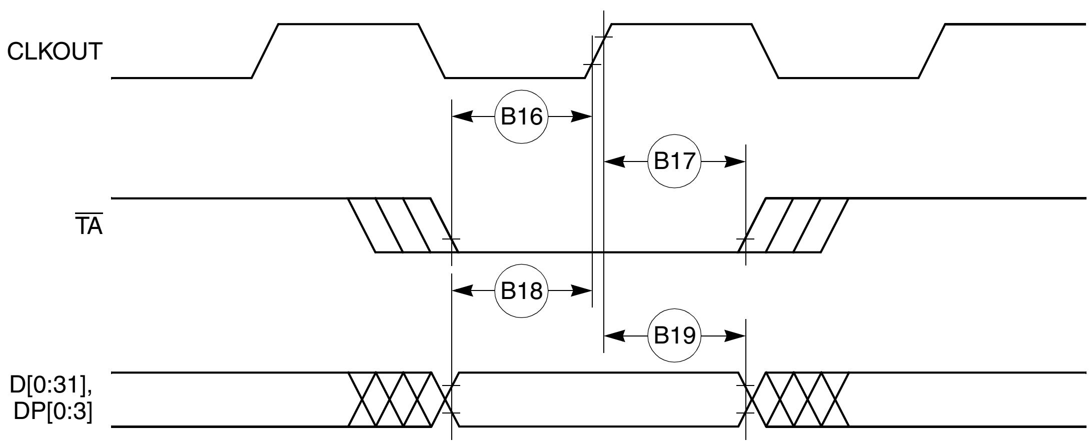


Figure 8. Input Data Timing in Normal Case

Figure 9 provides the timing for the input data controlled by the UPM for data beats where DLT3 = 1 in the UPM RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

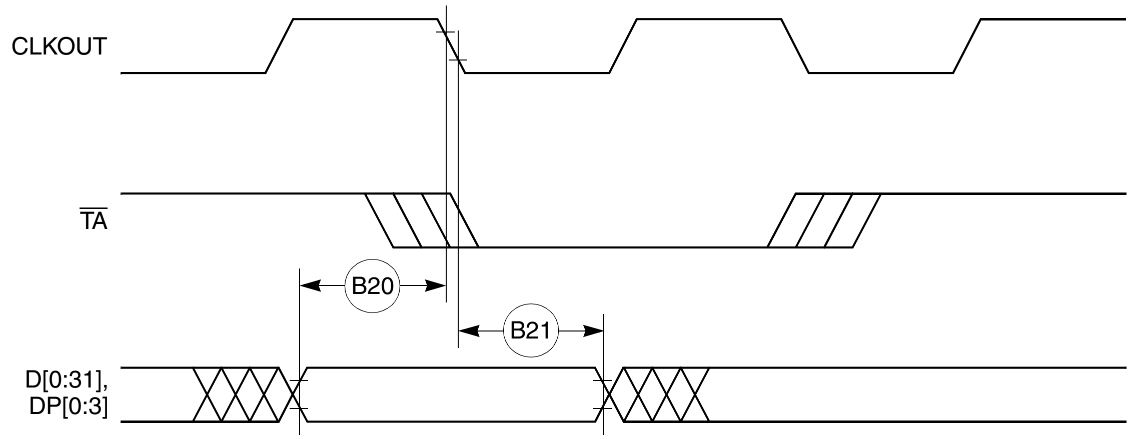


Figure 9. Input Data Timing when Controlled by UPM in the Memory Controller and DLT3 = 1

Figure 10 through Figure 13 provide the timing for the external bus read controlled by various GPCM factors.

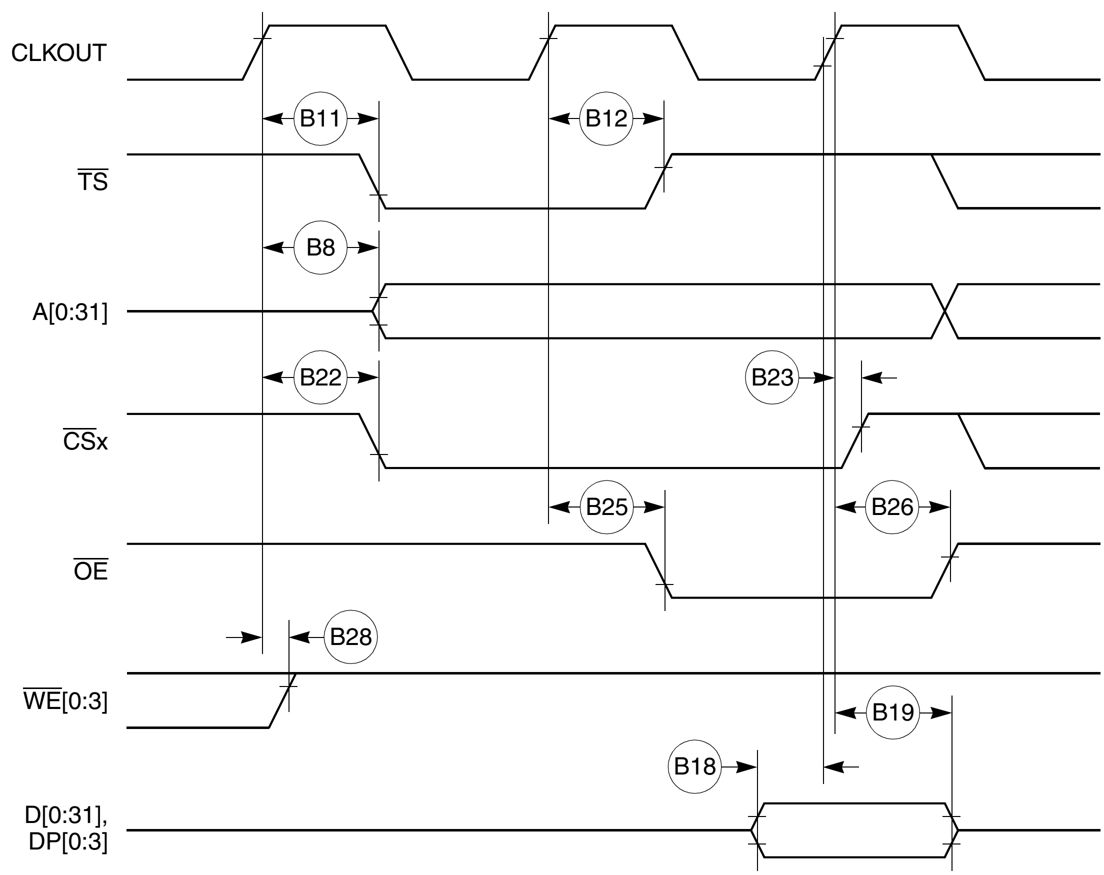


Figure 10. External Bus Read Timing (GPCM Controlled—ACS = 00)

Figure 20 provides the timing for the synchronous external master access controlled by the GPCM.

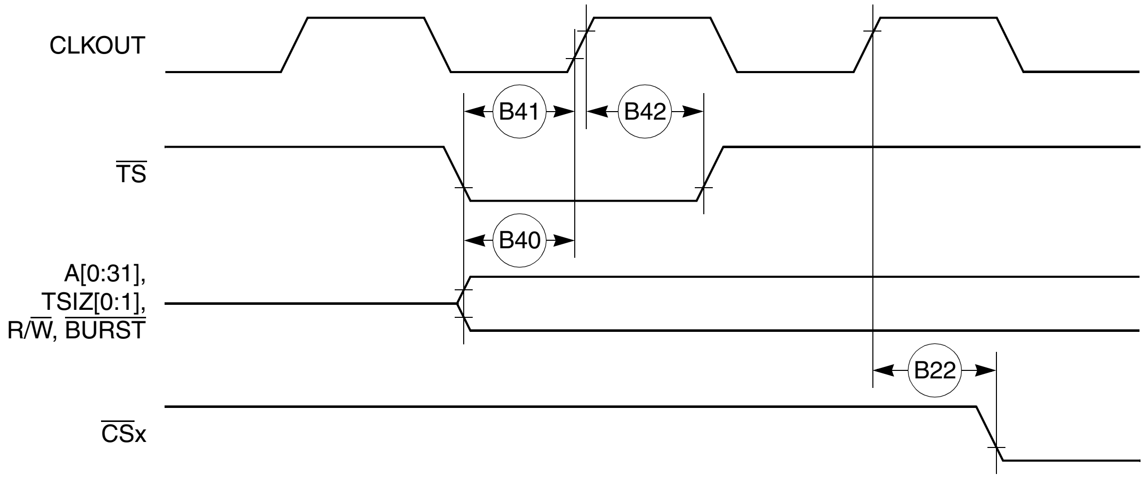


Figure 20. Synchronous External Master Access Timing (GPCM Handled ACS = 00)

Figure 21 provides the timing for the asynchronous external master memory access controlled by the GPCM.

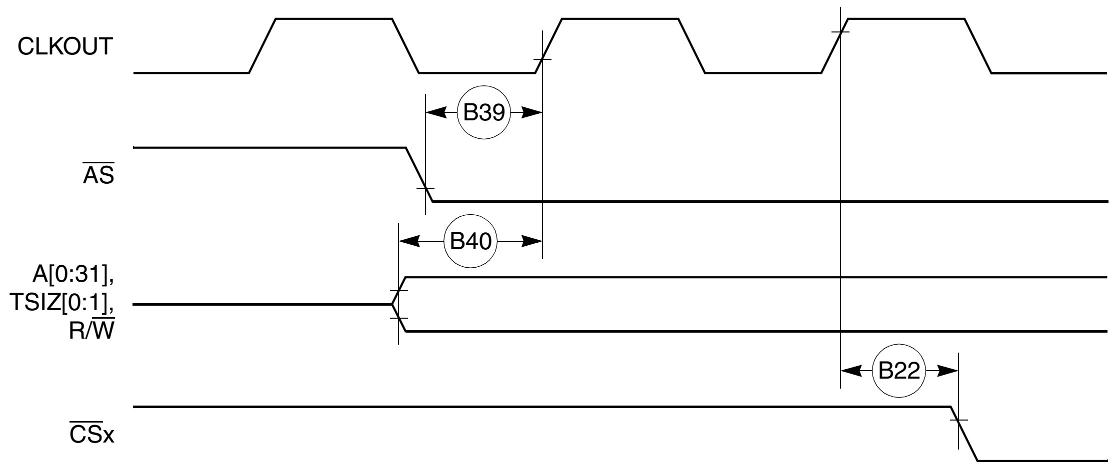


Figure 21. Asynchronous External Master Memory Access Timing (GPCM Controlled—ACS = 00)

Figure 22 provides the timing for the asynchronous external master control signals negation.

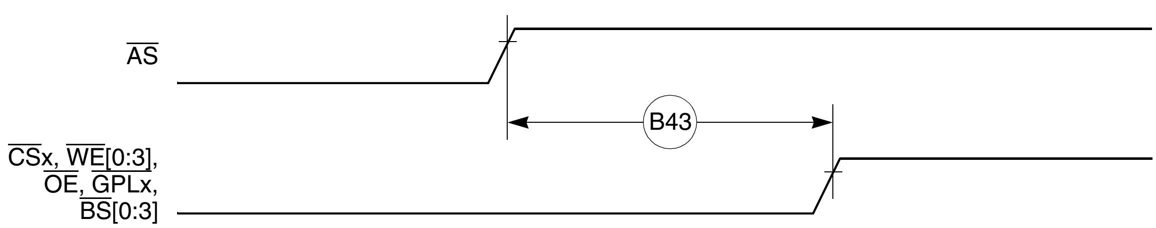


Figure 22. Asynchronous External Master—Control Signals Negation Timing

Table 8 provides interrupt timing for the MPC860.

Table 8. Interrupt Timing

Num	Characteristic[1]	All Frequencies		Unit
		Min	Max	
I39	$\overline{\text{IRQ}}$x valid to CLKOUT rising edge (setup time)	6.00	—	ns
I40	$\overline{\text{IRQ}}$x hold time after CLKOUT	2.00	—	ns
I41	$\overline{\text{IRQ}}$x pulse width low	3.00	—	ns
I42	$\overline{\text{IRQ}}$x pulse width high	3.00	—	ns
I43	$\overline{\text{IRQ}}$x edge-to-edge time	$4 \times T_{CLOCKOUT}$	—	—

[1] The timings I39 and I40 describe the testing conditions under which the $\overline{\text{IRQ}}$ lines are tested when being defined as level-sensitive. The $\overline{\text{IRQ}}$ lines are synchronized internally and do not have to be asserted or negated with reference to the CLKOUT.
The timings I41, I42, and I43 are specified to allow the correct function of the $\overline{\text{IRQ}}$ lines detection circuitry and have no direct relation with the total system interrupt latency that the MPC860 is able to support.

Figure 23 provides the interrupt detection timing for the external level-sensitive lines.

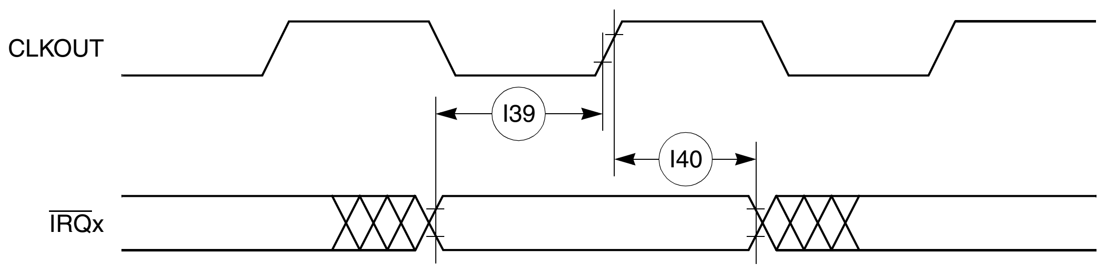


Figure 23. Interrupt Detection Timing for External Level Sensitive Lines

Figure 24 provides the interrupt detection timing for the external edge-sensitive lines.

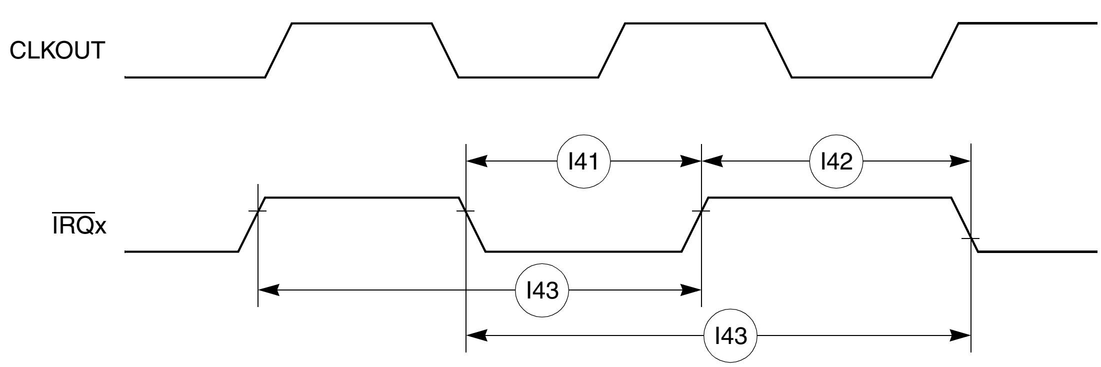


Figure 24. Interrupt Detection Timing for External Edge Sensitive Lines

Table 10 shows the PCMCIA port timing for the MPC860.

Table 10. PCMCIA Port Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
P57	CLKOUT to OPx valid	—	19.00	—	19.00	—	19.00	—	19.00	ns
P58	$\overline{\text{HRESET}}$ negated to OPx drive[1]	25.73	—	21.75	—	18.00	—	14.36	—	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	—	5.00	—	5.00	—	5.00	—	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	—	1.00	—	1.00	—	1.00	—	ns

[1] OP2 and OP3 only.

Figure 28 provides the PCMCIA output port timing for the MPC860.

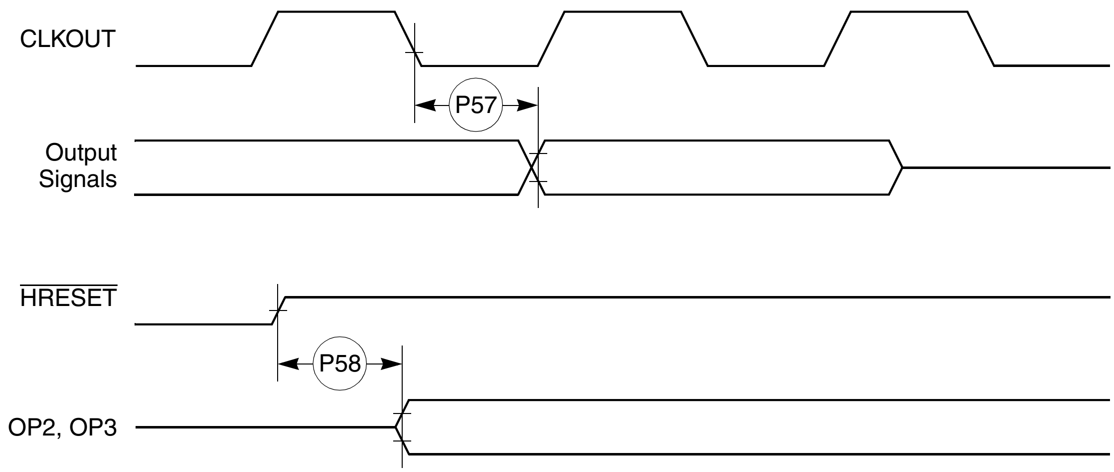


Figure 28. PCMCIA Output Port Timing

Figure 29 provides the PCMCIA output port timing for the MPC860.

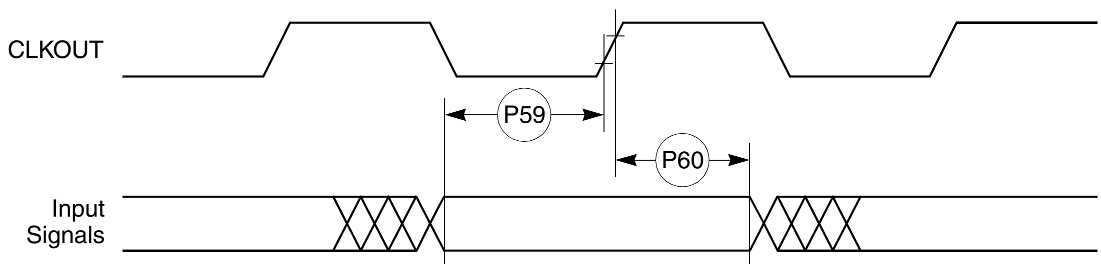


Figure 29. PCMCIA Input Port Timing

Table 12 shows the reset timing for the MPC860.

Table 12. Reset Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
R69	CLKOUT to $\overline{\text{HRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R70	CLKOUT to $\overline{\text{SRESET}}$ high impedance	—	20.00	—	20.00	—	20.00	—	20.00	ns
R71	$\overline{\text{RSTCONF}}$ pulse width	515.15	—	425.00		340.00	—	257.58	—	ns
R72	—	—	—	—	—	—	—	—	—	
R73	Configuration data to HRESET rising edge setup time	504.55	—	425.00	—	350.00	—	277.27	—	ns
R74	Configuration data to $\overline{\text{RSTCONF}}$ rising edge setup time	350.00	—	350.00	—	350.00	—	350.00	—	ns
R75	Configuration data hold time after $\overline{\text{RSTCONF}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R76	Configuration data hold time after $\overline{\text{HRESET}}$ negation	0.00	—	0.00	—	0.00	—	0.00	—	ns
R77	$\overline{\text{HRESET}}$ and $\overline{\text{RSTCONF}}$ asserted to data out drive	—	25.00		25.00	—	25.00	—	25.00	ns
R78	$\overline{\text{RSTCONF}}$ negated to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R79	CLKOUT of last rising edge before chip three-state $\overline{\text{HRESET}}$ to data out high impedance	—	25.00	—	25.00	—	25.00	—	25.00	ns
R80	DSDI, DSCK setup	90.91	—	75.00	—	60.00	—	45.45	—	ns
R81	DSDI, DSCK hold time	0.00	—	0.00	—	0.00	—	0.00	—	ns
R82	$\overline{\text{SRESET}}$ negated to CLKOUT rising edge for DSDI and DSCK sample	242.42	—	200.00	—	160.00	—	121.21	—	ns

Table 16. IDMA Controller Timing (continued)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
42	$\overline{\text{SDACK}}$ assertion delay from clock high	—	12	ns
43	$\overline{\text{SDACK}}$ negation delay from clock low	—	12	ns
44	$\overline{\text{SDACK}}$ negation delay from $\overline{\text{TA}}$ low	—	20	ns
45	$\overline{\text{SDACK}}$ negation delay from clock high	—	15	ns
46	$\overline{\text{TA}}$ assertion to rising edge of the clock setup time (applies to external $\overline{\text{TA}}$)	7	—	ns

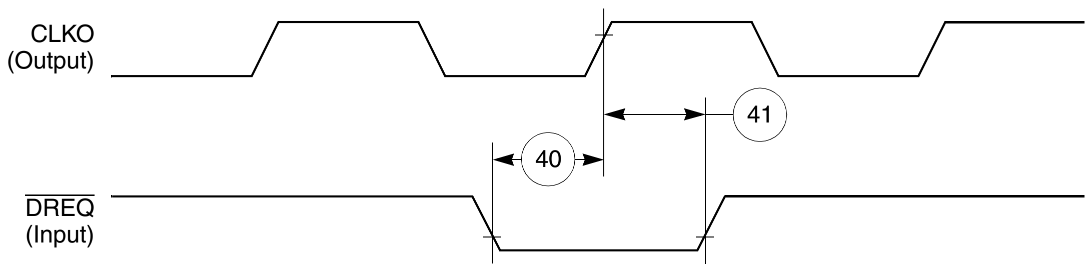


Figure 45. IDMA External Requests Timing Diagram

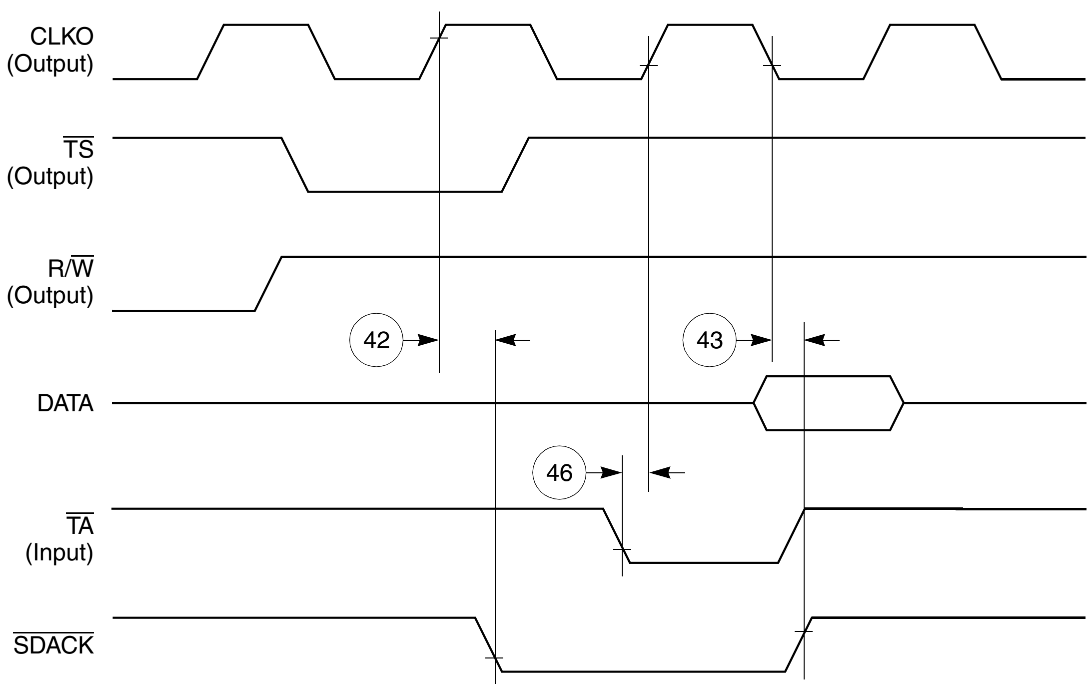


Figure 46. $\overline{\text{SDACK}}$ Timing Diagram—Peripheral Write, Externally-Generated $\overline{\text{TA}}$

11.4 Baud Rate Generator AC Electrical Specifications

Table 17 provides the baud rate generator timings as shown in Figure 49.

Table 17. Baud Rate Generator Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
50	BRGO rise and fall time	—	10	ns
51	BRGO duty cycle	40	60	%
52	BRGO cycle	40	—	ns

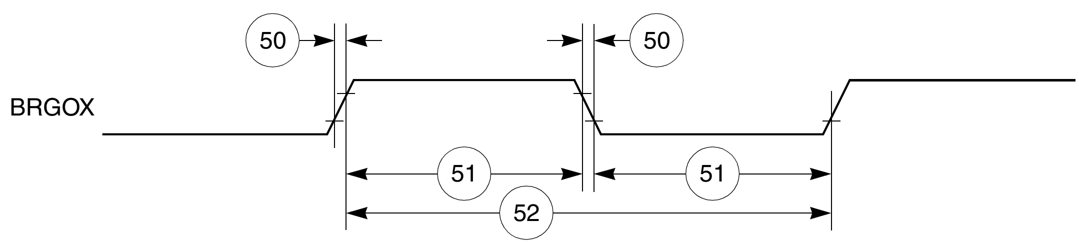


Figure 49. Baud Rate Generator Timing Diagram

11.5 Timer AC Electrical Specifications

Table 18 provides the general-purpose timer timings as shown in Figure 50.

Table 18. Timer Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
61	TIN/$\overline{\text{TGATE}}$ rise and fall time	10	—	ns
62	TIN/$\overline{\text{TGATE}}$ low time	1	—	CLK
63	TIN/$\overline{\text{TGATE}}$ high time	2	—	CLK
64	TIN/$\overline{\text{TGATE}}$ cycle time	3	—	CLK
65	CLKO low to $\overline{\text{TOUT}}$ valid	3	25	ns

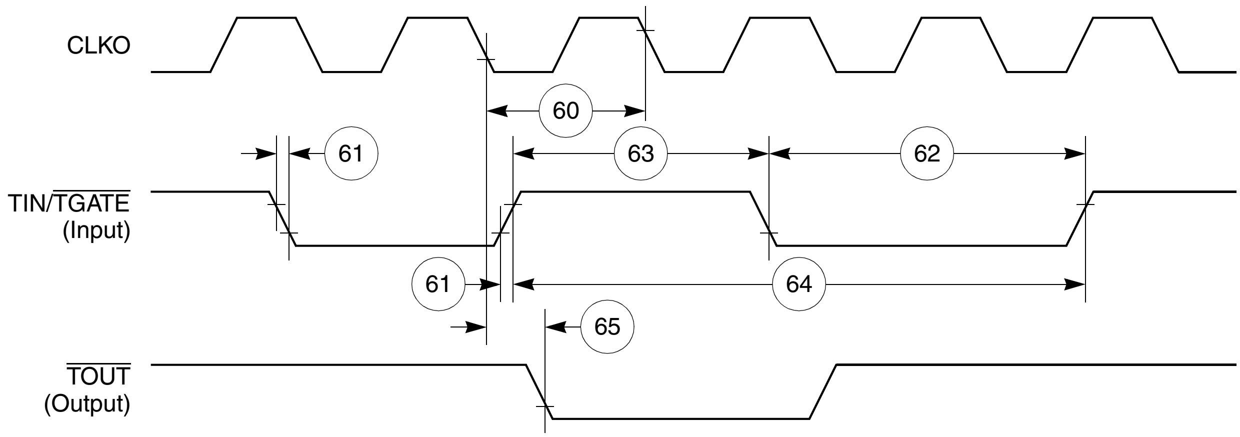


Figure 50. CPM General-Purpose Timers Timing Diagram

11.6 Serial Interface AC Electrical Specifications

Table 19 provides the serial interface timings as shown in Figure 51 through Figure 55.

Table 19. SI Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
70	L1RCLK, L1TCLK frequency (DSC = 0)[1, 2]	—	SYNCCLK/2.5	MHz
71	L1RCLK, L1TCLK width low (DSC = 0)[2]	P + 10	—	ns
71a	L1RCLK, L1TCLK width high (DSC = 0)[3]	P + 10	—	ns
72	L1TXD, L1ST(1–4), $\overline{\text{L1RQ}}$, L1CLKO rise/fall time	—	15.00	ns
73	L1RSYNC, L1TSYNC valid to L1CLK edge (SYNC setup time)	20.00	—	ns
74	L1CLK edge to L1RSYNC, L1TSYNC, invalid (SYNC hold time)	35.00	—	ns
75	L1RSYNC, L1TSYNC rise/fall time	—	15.00	ns
76	L1RXD valid to L1CLK edge (L1RXD setup time)	17.00	—	ns
77	L1CLK edge to L1RXD invalid (L1RXD hold time)	13.00	—	ns
78	L1CLK edge to L1ST(1–4) valid [4]	10.00	45.00	ns
78A	L1SYNC valid to L1ST(1–4) valid	10.00	45.00	ns
79	L1CLK edge to L1ST(1–4) invalid	10.00	45.00	ns
80	L1CLK edge to L1TXD valid	10.00	55.00	ns
80A	L1TSYNC valid to L1TXD valid [4]	10.00	55.00	ns
81	L1CLK edge to L1TXD high impedance	0.00	42.00	ns
82	L1RCLK, L1TCLK frequency (DSC =1)	—	16.00 or SYNCCLK/2	MHz
83	L1RCLK, L1TCLK width low (DSC = 1)	P + 10	—	ns
83a	L1RCLK, L1TCLK width high (DSC = 1)[3]	P + 10	—	ns

11.7 SCC in NMSI Mode Electrical Specifications

Table 20 provides the NMSI external clock timing.

Table 20. NMSI External Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK1 and TCLK1 width high[1]	1/SYNCCLK	—	ns
101	RCLK1 and TCLK1 width low	1/SYNCCLK + 5	—	ns
102	RCLK1 and TCLK1 rise/fall time	—	15.00	ns
103	TXD1 active delay (from TCLK1 falling edge)	0.00	50.00	ns
104	$\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge)	0.00	50.00	ns
105	$\overline{\text{CTS1}}$ setup time to TCLK1 rising edge	5.00	—	ns
106	RXD1 setup time to RCLK1 rising edge	5.00	—	ns
107	RXD1 hold time from RCLK1 rising edge[2]	5.00	—	ns
108	$\overline{\text{CD1}}$ setup Time to RCLK1 rising edge	5.00	—	ns

[1] The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 2.25/1.
[2] Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

Table 21 provides the NMSI internal clock timing.

Table 21. NMSI Internal Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK1 and TCLK1 frequency[1]	0.00	SYNCCLK/3	MHz
102	RCLK1 and TCLK1 rise/fall time	—	—	ns
103	TXD1 active delay (from TCLK1 falling edge)	0.00	30.00	ns
104	$\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge)	0.00	30.00	ns
105	$\overline{\text{CTS1}}$ setup time to TCLK1 rising edge	40.00	—	ns
106	RXD1 setup time to RCLK1 rising edge	40.00	—	ns
107	RXD1 hold time from RCLK1 rising edge[2]	0.00	—	ns
108	$\overline{\text{CD1}}$ setup time to RCLK1 rising edge	40.00	—	ns

[1] The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 3/1.
[2] Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

Figure 56 through Figure 58 show the NMSI timings.

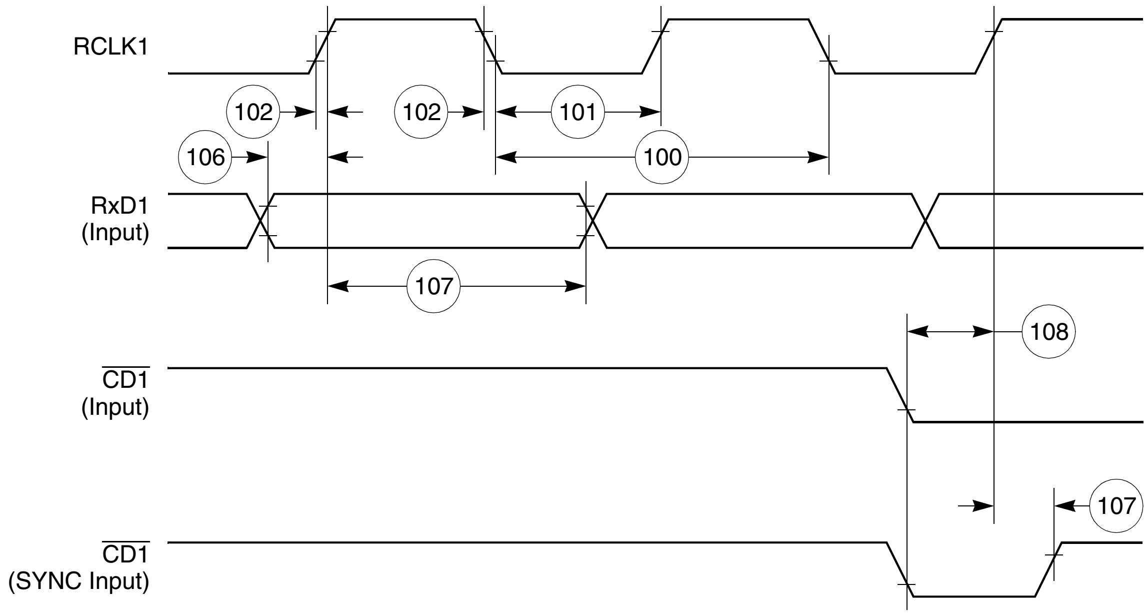


Figure 56. SCC NMSI Receive Timing Diagram

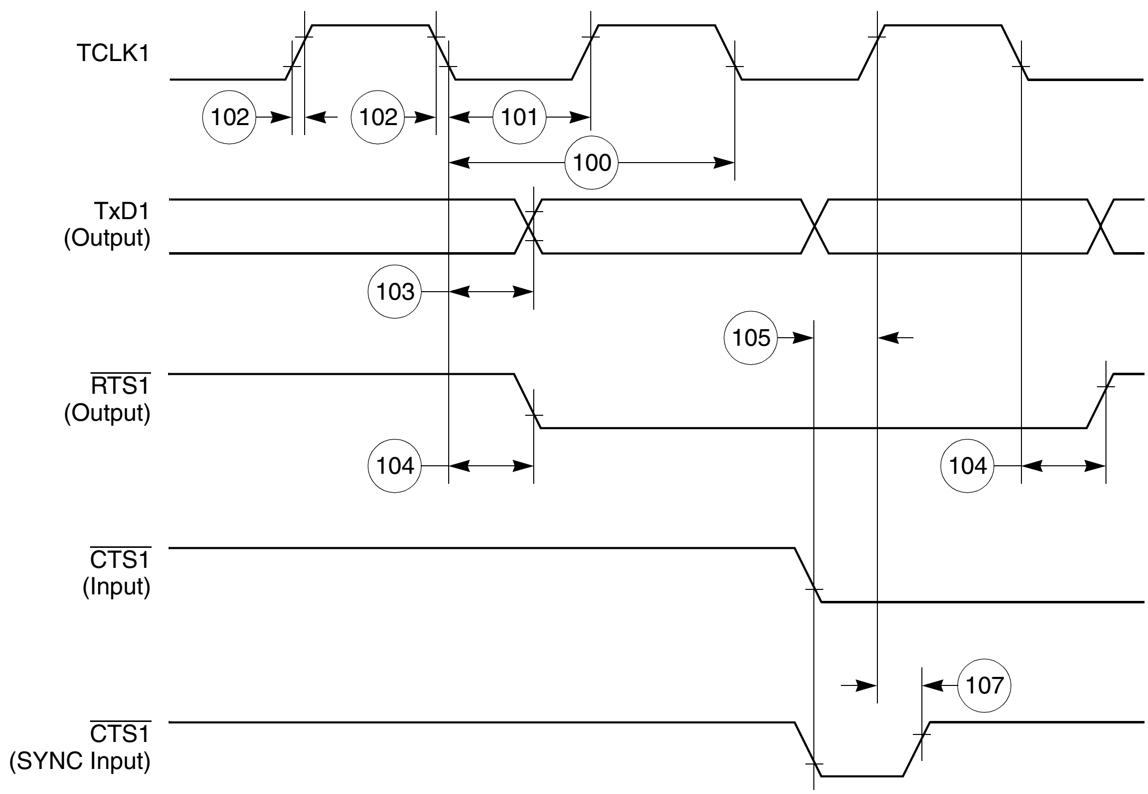


Figure 57. SCC NMSI Transmit Timing Diagram

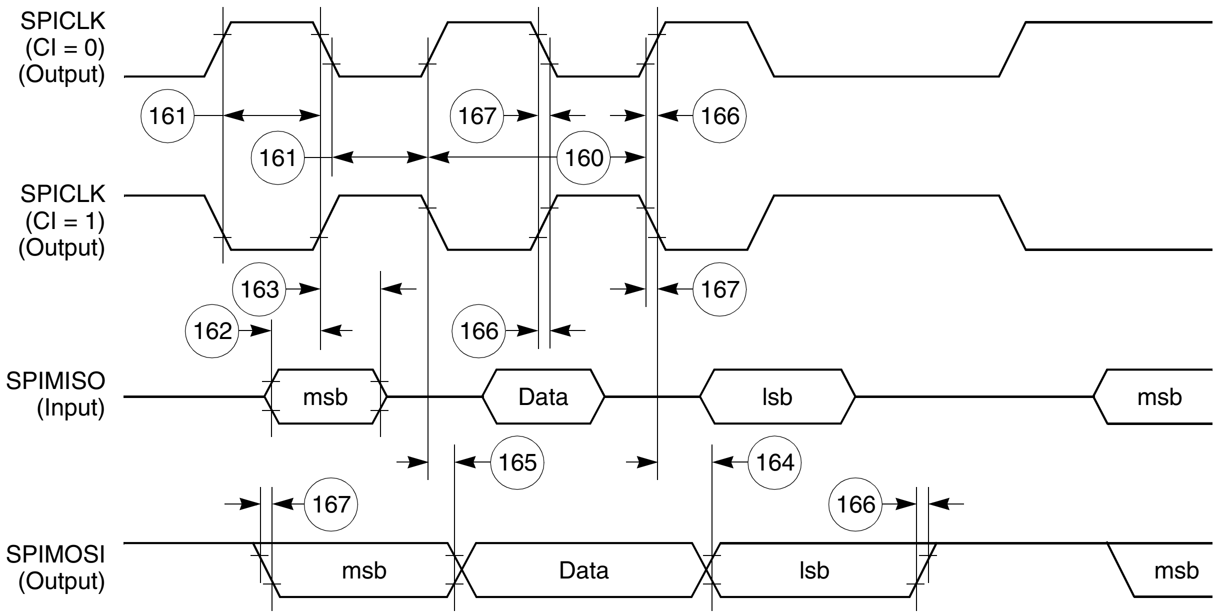


Figure 66. SPI Master (CP = 1) Timing Diagram

11.11 SPI Slave AC Electrical Specifications

Table 25 provides the SPI slave timings as shown in Figure 67 and Figure 68.

Table 25. SPI Slave Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
170	Slave cycle time	2	—	t_{cyc}
171	Slave enable lead time	15	—	ns
172	Slave enable lag time	15	—	ns
173	Slave clock (SPICLK) high or low time	1	—	t_{cyc}
174	Slave sequential transfer delay (does not require deselect)	1	—	t_{cyc}
175	Slave data setup time (inputs)	20	—	ns
176	Slave data hold time (inputs)	20	—	ns
177	Slave access time	—	50	ns

11.12 I²C AC Electrical Specifications

Table 26 provides the I²C (SCL < 100 kHz) timings.

Table 26. I²C Timing (SCL < 100 kHz)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
200	SCL clock frequency (slave)	0	100	kHz
200	SCL clock frequency (master)[1]	1.5	100	kHz
202	Bus free time between transmissions	4.7	—	μs
203	Low period of SCL	4.7	—	μs
204	High period of SCL	4.0	—	μs
205	Start condition setup time	4.7	—	μs
206	Start condition hold time	4.0	—	μs
207	Data hold time	0	—	μs
208	Data setup time	250	—	ns
209	SDL/SCL rise time	—	1	μs
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	μs

[1] SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3 × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I²C (SCL > 100 kHz) timings.

Table 27. . I²C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master)[1]	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		1/(2.2 * fSCL)	—	s
203	Low period of SCL		1/(2.2 * fSCL)	—	s
204	High period of SCL		1/(2.2 * fSCL)	—	s
205	Start condition setup time		1/(2.2 * fSCL)	—	s
206	Start condition hold time		1/(2.2 * fSCL)	—	s
207	Data hold time		0	—	s
208	Data setup time		1/(40 * fSCL)	—	s
209	SDL/SCL rise time		—	1/(10 * fSCL)	s
210	SDL/SCL fall time		—	1/(33 * fSCL)	s
211	Stop condition setup time		1/2(2.2 * fSCL)	—	s

[1] SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3) × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

Figure 69 shows the I^2C bus timing.

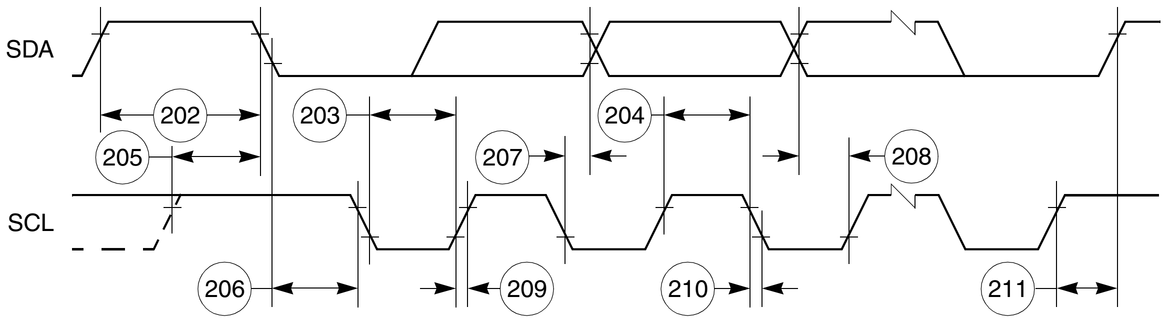


Figure 69. I^2C Bus Timing Diagram

12 UTOPIA AC Electrical Specifications

Table 28 shows the AC electrical specifications for the UTOPIA interface.

Table 28. UTOPIA AC Electrical Specifications

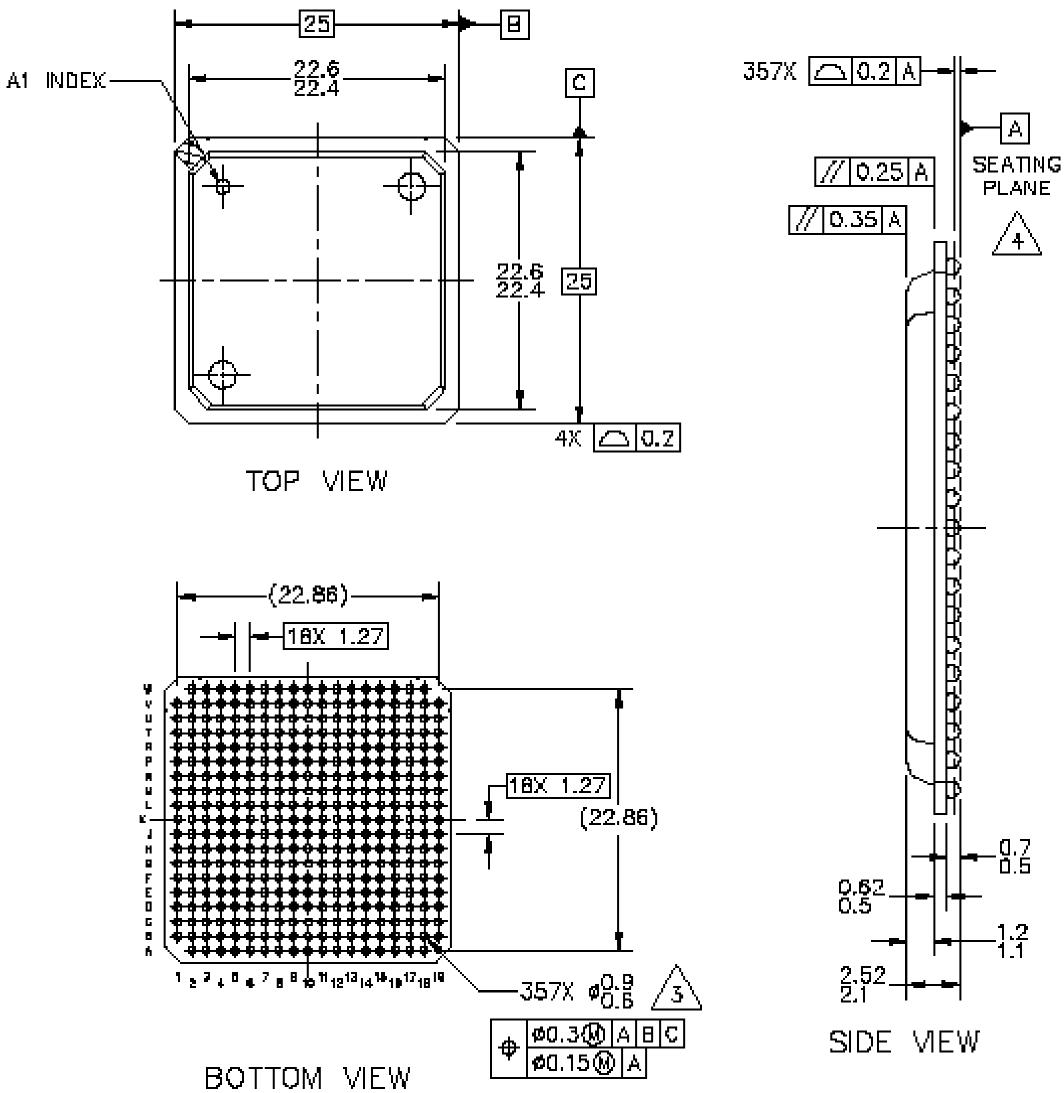
Num	Signal Characteristic	Direction	Min	Max	Unit
U1	UtpClk rise/fall time (Internal clock option)	Output	—	3.5	ns
	Duty cycle		50	50	%
	Frequency		—	50	MHz
U1a	UtpClk rise/fall time (external clock option)	Input	—	3.5	ns
	Duty cycle		40	60	%
	Frequency		—	50	MHz
U2	$\overline{\text{RxEnb}}$ and $\overline{\text{TxEnb}}$ active delay	Output	2	16	ns
U3	UTPB, SOC, Rxclav and Txclav setup time	Input	8	—	ns
U4	UTPB, SOC, Rxclav and Txclav hold time	Input	1	—	ns
U5	UTPB, SOC active delay (and PHREQ and PHSEL active delay in MPHY mode)	Output	2	16	ns

Table 34. MPC860 Family Package/Frequency Availability (continued)

Package Type	Freq. (MHz) / Temp. (Tj)	Package	Order Number
Ball grid array *(continued)* ZP suffix—leaded ZQ suffix—leaded VR suffix—lead-free	80 0° to 95°C	ZP/ZQ[1]	MPC855TZQ80D4 MPC860DEZQ80D4 MPC860DTZQ80D4 MPC860ENZQ80D4 MPC860SRZQ80D4 MPC860TZQ80D4 MPC860DPZQ80D4 MPC860PZQ80D4
		Tape and Reel	MPC860PZQ80D4R2 MPC860PVR80D4R2
		VR	MPC855TVR80D4 MPC860DEVR80D4 MPC860DPVR80D4 MPC860ENVR80D4 MPC860PVR80D4 MPC860SRVR80D4 MPC860TVR80D4
Ball grid array (CZP suffix) CZP suffix—leaded CZQ suffix—leaded CVR suffix—lead-free	50 –40° to 95°C	ZP/ZQ[1]	MPC855TCZQ50D4 MPC855TCVR50D4 MPC860DECZQ50D4 MPC860DTCZQ50D4 MPC860ENCZQ50D4 MPC860SRCZQ50D4 MPC860TCZQ50D4 MPC860DPCZQ50D4 MPC860PCZQ50D4
		Tape and Reel	MPC855TCZQ50D4R2 MC860ENCVR50D4R2
		CVR	MPC860DECVR50D4 MPC860DTCVR50D4 MPC860ENCVR50D4 MPC860PCVR50D4 MPC860SRCVR50D4 MPC860TCVR50D4
	66 –40° to 95°C	ZP/ZQ[1]	MPC855TCZQ66D4 MPC855TCVR66D4 MPC860ENCZQ66D4 MPC860SRCZQ66D4 MPC860TCZQ66D4 MPC860DPCZQ66D4 MPC860PCZQ66D4
		CVR	MPC860DTCVR66D4 MPC860ENCVR66D4 MPC860PCVR66D4 MPC860SRCVR66D4 MPC860TCVR66D4

[1] The ZP package is no longer recommended for use. The ZQ package replaces the ZP package.

Figure 78 shows the mechanical dimensions of the ZQ PBGA package.



NOTE

1. All Dimensions in millimeters.
2. Dimensions and tolerance per ASME Y14.5M, 1994.
3. Maximum Solder Ball Diameter measured parallel to Datum A.
4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.

Figure 78. Mechanical Dimensions and Bottom Surface Nomenclature of the ZQ PBGA Package